## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | BENCO ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,704,812 B2	03-2004	Bakke et al.	710/38
	В	US-2004/0225804 A1	11-2004	Leete, Brian A.	710/305
	С	US-2005/0015536 A1	01-2005	Lee, Kuei-Jung	710/313
	D	US-2004/0198429 A1	10-2004	Yen et al.	455/556.1
	E	US-2003/0135681 A1	07-2003	Laity et al.	710/303
	F	US-2004/0133722 A1	07-2004	Croyle et al.	710/105
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	α	•				
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.